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PATENT NUMBER	
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O.I.P.E.	PATENT DATE
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APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT EXAMINER

99/975835 F 324 715 2857

Hiroshi Koshiba - 7/4 RSD/n OL 2133 TRIMMINES

701

Semiconductor test apparatus and control method therefor

ORIGINAL CLASSIFICATION

CLASS SUBCLASS CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)

INTERNATIONAL CLASSIFICATION

ORIGINAL C

TERMINAL	DRAWINGS		CLAIMS ALLOWED		
DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
The term of this patent subsequent to (date)				NOTICE OF ALI	LOWANCE MAILED
has been disclaimed.  The term of this patent shall not extend beyond the expiration date	(Assistant	Examiner)	(Date)	100	
of U.S Patent. No.			ISSUE FEE		
	(Dimer.	Examiner)	(Date)	Amount Due	Date Paid
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